BUREAU OF INDIAN STANDARDS

Program of Work

LITD 5: Semiconductor And Other Electronic Components And Devices

Scope: To prepare Indian standards relating to: a) Semiconductor devices & integrated circuits. b)

Capacitors, resistrs, allied component c) Discrete semiconductor devices & micro-

electromechanical systems d) Electronic assembly technologies and printed board assemblies.

e) Capacitors resistors and inductors for use in electronics equipment.

Liaison: IEC TC-40 (P): Capacitors and resistors for electronic equipment IEC

TC-47 (O): Semiconductor devices IEC TC-47 SC-47A (O): Integrated circuits IEC

TC-91 (P): Electronics assembly technology IEC TC-91 (P): Requirements for electronic

components IEC TC-91 (P): Requirements for electronics assemblies IEC

TC-91 (P): Measuring and test methods for electronics assemblies IEC TC-91 (P): Printed boards and materials IEC TC-91 (P): Vocabulary IEC TC-91 (P): Measuring and test methods for circuit boards and circuit board materials IEC TC-91 (P): Design methodology and data transfer of circuit boards and circuit board assemblies

Published Standards

S.No	IS No.	TITLE	Reaffirm M-Y	No. of Amds	Eqv.
1	IS/QC 001001:2000	IEC quality assessment system for	March, 2024	-	Identical under single
	Reviewed In: 2024	electronic components (IECQ) -			numbering
	IECQC 001001	Basic rules (First Revision)			
2	IS/QC	IEC quality assessment system for	March, 2024	-	Identical under single
	001002-1:2000	electronic components (IECQ) -			numbering
	Reviewed In: 2024	Rules of procedure: Part 1			
	IECQC	administration (First Revision)			
	001002-1:1998				
3	IS/QC	IEC quality assessment system for	March, 2024	=	Identical under single
	001002-2:2000	electronic components (IECQ) -			numbering
	Reviewed In: 2024	Rules of procedure: Part 2			
	IECQC 001002-2:	Documentation (First Revision)			
	1998				
4	IS/QC	IEC quality assessment system for	March, 2024	=	Identical under single
	001002-3:2000	electronic components (IECQ) -			numbering
	Reviewed In: 2024	Rules of procedure: Part 3 approval			
	IEC QC 001002-3	procedures (First Revision)			
	:1998				
5	IS/QC 001003:2000	IEC quality assessment system for	March, 2024	-	Identical under single
	Reviewed In: 2024	electronic components (IECQ) -			numbering
	IECQC 001003	Guidance documents			
6	IS 10249 (Part	Specification for voltage dependent	December, 2021	-	Indigenous
	1):1982	resistors (Varistors): Part 1 general			
	Reviewed In: 2021	requirements and methods of tests			
7	IS 11392 (Part 1/Sec	Dimensions of mounting	February, 2023	-	Indigenous
	2):1988	accessories of pot cores for printed			
	Reviewed In: 2023	circuit board mountings: Part 1 for			
I		ı		1	l l

		pot core of size 18 x 11 mm: Sec 2			
8	IS 11534 (Part 1):1985 Reviewed In : 2021 IEC 60738-1 :1982	type 2 Specification for directly heated positive step - Function temperature coefficient thermistors: Part 1 general requirements and methods of tests	December, 2021	-	Modified/Technically Equivalent
9	IS 12970 (Part 1):2010 Reviewed In : 2021 IEC 60748-1:2002	Semiconductor devices integrated circuits: Part 1 general	December, 2021	-	Identical under dual numbering
10	IS 12970 (Part 2):2021 IEC 60748-2: 1997 Reviewed In : 2024 IEC 60748-2: 1997	Semiconductor devices - Integrated circuits: Part 2 Digital integrated circuits essential ratings and characteristics Sec 1 General	March, 2024	-	Identical under dual numbering
11	IS 12970 (Part	Semiconductor devices Integrated circuits Part 3 Analogue integrated circuits Superseding 1 IS 12970Part 5Sec 1:1991 2 IS 12970Part 5Sec 2:1992 3 IS 12970Part 5Sec 3:1992 4 IS 12970Part 5Sec 4:1992 5 IS 12970Part 5Sec 5:1993 6 IS 12970Part 5Sec		-	Identical under dual numbering
12	IS 13247 (Part 1):2021 IEC 60939-1: 2010 IEC 60939-1: 2010	Passive filter units for electromagnetic interference suppression Part 1 Generic specification First Revision and Superseding 1 IS 3723Part 1:1978 2 IS 3723Part 2:1983 and 3 IS 3723Part 3:1983		-	Identical under dual numbering
13	IS 13247 (Part 2):2021 IEC 60939-2:2005 IEC 60939-2:2005	Passive filter units for electromagnetic interference suppression Part 2 Sectional specification Passive filter units for which safety tests are appropriate Test methods and general requirements First Revision of IS 13247 Part 2		-	Identical under dual numbering
14	IEC 60294 : 2012	Measurement of the Dimensions of a Cylindrical Component with Axial Terminations (First Revision)	-	-	Identical under dual numbering
15	IS 13562:1992 Reviewed In : 2021 IEC 60824	Terminology related to microprocessors	December, 2021	-	Modified/Technically Equivalent
16	IS 14901 (Part	Semiconductor devices - Discrete devices and integrated circuits: Part 1 general (First Revision)	February, 2022	-	Identical under dual numbering
17	IS 14901 (Part 2):2020 IEC 60747-2: 2016 IEC 60747-2: 2016	Semiconductor Devices Part 2 Discrete Devices — Rectifier Diodes (First Revision)	-	-	Identical under dual numbering
18	IS 14901 (Part 3):2016 IEC 60747-3: 2013	Semiconductor Devices Discrete Devices Part 3 Signal, Switching and Regulator Diodes	August, 2022	-	Identical under dual numbering

	Reviewed In: 2022			I	
	IEC 60747-3				
19	IS 14901 (Part	Semiconductor devices - Discrete	December, 2021	2	Identical under dual
	· ·	devices and integrated circuits: Part			numbering
	IEC 60747-5	5 optoelectronic devices			
	Reviewed In: 2021				
	IEC 60747-5:1992				
20	IS 14901 (Part	Semiconductor Devices —	-	-	Identical under dual
	7):2020	Discrete Devices Part 7 Bipolar			numbering
	IEC 60747-7 : 2010	` ′			
L	IEC 60747-7 : 2010				
21	IS 14901 (Part	Semiconductor Devices —	-	-	Identical under dual
	8):2020	Discrete Devices Part 8 Field-			numbering
	IEC 60747-8 : 2010	`			
	IEC 60747-8 : 2010		D 1 2021		71 . 1 1 1 1 1
22	IS 15866 (Part	Fixed inductors for	December, 2021	-	Identical under dual
	1):2010	electromagnetic interference			numbering
	IEC 60938-1:2006	suppression: Part 1 generic			
	Reviewed In: 2021	specification			
22	IEC 60938-1:2006	Fixed conscitous for the in	March, 2021	+	Identical under single
23	IS/QC 300000:1988 Reviewed In : 2021	Fixed capacitors for use in	march, 2021	-	Identical under single
		electronic equipment generic			numbering
24	IECQC 300000:1982 IS/QC 300100:1988		March, 2021	+	Identical under single
24	Reviewed In : 2021	*	March, 2021	-	· ·
	IECQC 300100:	electronic equipment: Sectional specification: fixed polyethrsylene			numbering
	1982	- Terephthalate film dielectric			
	1982	metal foil DC capacitor			
25	IS/QC 300201:2000	Fixed capacitors for use in	March, 2021	1	Identical under single
23	Reviewed In : 2021	electronic equipment: Part 15	March, 2021	1	numbering
	IECQC 300201:	blank detail specification: fixed			numbering
	1984	tantalum capacitors with solid			
	1904	electrolyte and porous anode			
		assessment level E			
26	IS/QC 300301:1993		March, 2021	_	Identical under single
20	Reviewed In: 2021	electronic equipment blank detail	Waren, 2021		numbering
	Reaffirmed but not	specification aluminium			numbering
	taken up for revision	-			
	*	Solid electrolyte assessment level E			
	1985	some electrony to assessiment level E			
27	IS/QC 300401:1988	Fixed capacitors for use in	March, 2021	-	Identical under single
'	Reviewed In: 2021	electronic equipment blank detail	,		numbering
	Reaffirmed but not	specification fixed metallized			, 5
	taken up for revision	-			
	IECQC 300401:	dielectric D C capacitors			
	1982	assessment level e			
28	IS/QC 300600:1993		March, 2021	-	Identical under single
	Reviewed In: 2021	electronic equipment - Sectional	,		numbering
	IECQC 300600:	specification for fixed capacitors			
	1988	of ceramic dielectric, class 1			
29	IS/QC 300601:1993		March, 2021	-	Identical under single
	Reviewed In: 2021	electronic equipment,blank detail			numbering
	Reaffirmed but not	specification for fixed capacitors			
	taken up for revision	-			
	IECQC 300601:	1,assessment level E			
L	1988				
30	IS/QC 300701:1993		March, 2021	-	Identical under single
	Reviewed In: 2021	Electronic Equipment Sectional			numbering
	Reaffirmed but not	Fixed Capacitors of Ceramic			
I	I	ı		I	1

	taken up for revision	Dielectric, Class 2		1	Í I
	IECQC 300701:	·			
	1988				
31	IS/QC 300800:1994	Fixed capacitors for use in	September, 2020	-	Identical under single
	Reviewed In: 2020	electronic equipment: Sectional			numbering
	IECQC 300800:	specification for fixed tantalum			
	1989	chip capacitors			
32	IS/QC 300801:1993	Fixed capacitors for use in	September, 2020	-	Identical under single
	Reviewed In: 2020	electronic equipment blank detail			numbering
	Reaffirmed but not	specification for fixed tantalum			
	-	chip capacitors assessment level E			
<u></u>	IECQC 300801				
33	IS/QC 301200:1993	Fixed capacitors for use in	March, 2021	-	Identical under single
	Reviewed In: 2021	electronic equipment Sectional			numbering
	Reaffirmed but not	specification for fixed metallized			
	_	polypropylene film dielectric D.C.			
	IECQC 301200:	capacitors			
2.4	1982	Fixed conscitors for use in	March 2021		Identical under single
34	IS/QC 301201:1993 Reviewed In : 2021	Fixed capacitors for use in electronic equipment - Blank detail	March, 2021	_	Identical under single
	Reaffirmed but not	specification for fixed metallized			numbering
		polypropylene film dielectric D. C.			
	IECQC 301201:	capacitors - Assessment level e			
	1982	capacitors - Assessment lever c			
35	IS/QC 301301:1993	Fixed capacitors for use in	March, 2021	_	Identical under single
	Reviewed In : 2021	electronic equipment, blank detail	March, 2021		numbering
	Reaffirmed but not	specification for fixed metallized			namoering
		polypropylene film dielectric A.C.			
	IECQC 301301:	and pulse capacitors, assessment			
	1987	level E			
36	IS/QC 301800:2001	Fixed capacitors for use in	September, 2020	-	Identical under single
	~	electronic equipment: Part 13 Secal	1 ,		numbering
	IECQC 301800:	specification fixed polypropylene			
	1991	film dielectric metal foil D.C.			
		capacitors: Sec one - General			
37	IS/QC 301801:2001	Fixed capacitors for use in	September, 2020	-	Identical under single
	Reviewed In: 2020	electronic equipment: Part 13			numbering
	IECQC 301801:	blank detail specification fixed			
	1991	polypropylene film dielectric metal			
		foil D.C. capacitors assessment			
		*			
		level E			
38	IS/QC 302400:1994	level E Fixed capacitors for use in	March, 2018	-	Identical under single
38	Reviewed In: 2018	level E Fixed capacitors for use in electronic equipment: Sectional	March, 2018	-	Identical under single numbering
38	Reviewed In: 2018 IECQC 302400:	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors	March, 2018	-	
38	Reviewed In: 2018	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference	March, 2018	-	
38	Reviewed In: 2018 IECQC 302400:	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the	March, 2018	-	
	Reviewed In: 2018 IECQC 302400: 1993	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains		-	numbering
38	Reviewed In: 2018 IECQC 302400: 1993 IS/QC 400100:1988	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains Fixed resistors for use in electronic	March, 2018 March, 2021	-	numbering Identical under single
	Reviewed In: 2018 IECQC 302400: 1993 IS/QC 400100:1988 Reviewed In: 2021	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains Fixed resistors for use in electronic equipment: Sectional specification		-	numbering
	Reviewed In: 2018 IECQC 302400: 1993 IS/QC 400100:1988 Reviewed In: 2021 IECQC 400100:	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains Fixed resistors for use in electronic equipment: Sectional specification fixed low - Power non - Wire		-	numbering Identical under single
39	Reviewed In: 2018 IECQC 302400: 1993 IS/QC 400100:1988 Reviewed In: 2021 IECQC 400100: 1982	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains Fixed resistors for use in electronic equipment: Sectional specification fixed low - Power non - Wire wound resistors	March, 2021	-	numbering Identical under single numbering
39	Reviewed In: 2018 IECQC 302400: 1993 IS/QC 400100:1988 Reviewed In: 2021 IECQC 400100: 1982 IS/QC 400101:1988	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains Fixed resistors for use in electronic equipment: Sectional specification fixed low - Power non - Wire wound resistors Fixed restors for use in electronic		-	Identical under single numbering Identical under single
39	Reviewed In: 2018 IECQC 302400: 1993 IS/QC 400100:1988 Reviewed In: 2021 IECQC 400100: 1982 IS/QC 400101:1988 Reviewed In: 2021	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains Fixed resistors for use in electronic equipment: Sectional specification fixed low - Power non - Wire wound resistors Fixed restors for use in electronic equipment blank detail	March, 2021	-	numbering Identical under single numbering
39	Reviewed In: 2018 IECQC 302400: 1993 IS/QC 400100:1988 Reviewed In: 2021 IECQC 400100: 1982 IS/QC 400101:1988 Reviewed In: 2021 IECQC 400101:	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains Fixed resistors for use in electronic equipment: Sectional specification fixed low - Power non - Wire wound resistors Fixed restors for use in electronic equipment blank detail specification fixed low - Power	March, 2021	-	Identical under single numbering Identical under single
39	Reviewed In: 2018 IECQC 302400: 1993 IS/QC 400100:1988 Reviewed In: 2021 IECQC 400100: 1982 IS/QC 400101:1988 Reviewed In: 2021	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains Fixed resistors for use in electronic equipment: Sectional specification fixed low - Power non - Wire wound resistors Fixed restors for use in electronic equipment blank detail specification fixed low - Power non - Wirewound resistors	March, 2021	-	Identical under single numbering Identical under single
39	Reviewed In: 2018 IECQC 302400: 1993 IS/QC 400100:1988 Reviewed In: 2021 IECQC 400100: 1982 IS/QC 400101:1988 Reviewed In: 2021 IECQC 400101: 1982	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains Fixed resistors for use in electronic equipment: Sectional specification fixed low - Power non - Wire wound resistors Fixed restors for use in electronic equipment blank detail specification fixed low - Power non - Wirewound resistors assessment level E	March, 2021 March, 2021	-	Identical under single numbering Identical under single numbering
39	Reviewed In: 2018 IECQC 302400: 1993 IS/QC 400100:1988 Reviewed In: 2021 IECQC 400100: 1982 IS/QC 400101:1988 Reviewed In: 2021 IECQC 400101: 1982 IS/QC 400200:1992	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains Fixed resistors for use in electronic equipment: Sectional specification fixed low - Power non - Wire wound resistors Fixed restors for use in electronic equipment blank detail specification fixed low - Power non - Wirewound resistors assessment level E Fixed resistors for use in electronic	March, 2021	-	Identical under single numbering Identical under single numbering Identical under single numbering
39	Reviewed In: 2018 IECQC 302400: 1993 IS/QC 400100:1988 Reviewed In: 2021 IECQC 400100: 1982 IS/QC 400101:1988 Reviewed In: 2021 IECQC 400101: 1982 IS/QC 400200:1992	level E Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains Fixed resistors for use in electronic equipment: Sectional specification fixed low - Power non - Wire wound resistors Fixed restors for use in electronic equipment blank detail specification fixed low - Power non - Wirewound resistors assessment level E	March, 2021 March, 2021	-	Identical under single numbering Identical under single numbering

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42		Fixed resistors for use in electronic	March, 2021	-	Identical under single
		equipment - Sectional specification	,		numbering
	Reaffirmed but not	for fixed resistor networks with			
	taken up for revision				
	IECQC 400400:				
	1983				
43		Fixed resistors for use in electronic	March, 2021	-	Identical under single
	Reviewed In: 2021	equipment - Blank detail			numbering
	Reaffirmed but not	specification - Fixed resistor			_
	taken up for revision	networks with individually			
	IECQC 400401:	measurable resistors, all of equal			
	1983	value and equal dissipation			
		assessment level E			
44	IS/QC 400500:1993	Fixed resistors for use in electronic	March, 2021	-	Identical under single
	Reviewed In: 2021	equipment - Sectional specification			numbering
	Reaffirmed but not	for fixed resistor networks in			
	taken up for revision	which not all resistors are			
	IECQC 400500:	individually measurable			
	1984				
45	~	Fixed resistors for use in electronic	March, 2021	-	Identical under single
	Reviewed In: 2021	equipment - Blank detail			numbering
	Reaffirmed but not	specification for fixed resistors			
	-	networks in which not all resistors			
	IECQC 400501:	are individually measurable -			
	1984	Assessment level E			
46	~	Fixed resistors for use in electronic	March, 2021	-	Identical under single
		equipment: Sectional specification			numbering
	Reaffirmed but not	for fixed chip resistors			
	taken up for revision				
	IECQC 400600: 1989				
47		Fixed resistors for use in electronic	March, 2021		Identical under single
4/	Reviewed In : 2021	equipment blank detail	Maich, 2021	-	numbering
	Reaffirmed but not	specification for fixed chip			numbering
	taken up for revision	<u>.</u>			
	IECQC 400601:	resistors assessment rever E			
	1989				
48	IS/QC 410100:1992	Potentiometers for use in	March, 2021	_	Identical under single
	Reviewed In: 2021	electronic equipment Sectional			numbering
	Reaffirmed but not	specification lead - Screw actuated			
	taken up for revision	and rotary preset potentiometers			
	IECQC 410100:				
<u> </u>	1989				
49	IS/QC 410101:1992	Potentiometers for Use in	March, 2021	-	Identical under single
	Reviewed In: 2021	Electronic Equipment Blank Detail			numbering
	Reaffirmed but not	Specification: Lead-Screw			
	taken up for revision				
	IECQC 410101	Potentiometers Assessment Level			
	70.0 0 · · ·	Е			
50	IS/QC 420000:1994		November, 2023	-	Identical under single
	Reviewed In: 2023	equipment - Generic specification			numbering
F 1	IECQC 420000	Variatora for a service 1	Me::-1- 2021		Identical and a 1 1
51	IS/QC 420100:1994		March, 2021	-	Identical under single
	Reviewed In: 2021 Reaffirmed but not	equipmentSectional specification			numbering
	taken up for revision	for surge suppression varistors			
	IECQC 420100				
52	IS/QC 420100	Varistors for use in electronic	March, 2021		Identical under single
]	15/ 20 120102,1793	, aristors for use in electronic	17141011, 2021		Identical under single

ı	Reviewed In: 2021	aguinment Plenk datail	1	ı	l numbering
	Reaffirmed but not	1 1			numbering
		suppression varistors - AsiEssment			
	IECQC 420102	level E			
53	IS/QC 440000:1994		March, 2018	-	Identical under single
	Reviewed In: 2018	function temperature coefficient	1,141,011, 2010		numbering
	IECQC 440000	thermistors - Generic specification			
54	IS/QC 440001:1993		March, 2021	-	Identical under single
	Reviewed In: 2021	function temperature coefficient	,		numbering
	Reaffirmed but not	thermistors - Blank detail			
	taken up for revision	specification - Assessment level E			
	IECQC 440001				
55	IS 5001:2018	Mechanical standardization of	March, 2021	-	Identical under dual
	IEC 60191-1:2007	semiconductor devices - General			numbering
	Reviewed In: 2021	rules for the preparation of outline			
	IEC 60191-1:2007	drawings of discrete devices (First			
		Revision)			
56	IS 5001 (Part	Guide for Preparation of Drawings	March, 2021	1	Modified/Technically
	1):1969	of Semiconductor Devices			Equivalent
	Reviewed In: 2021				
	IEC 60191 - 1 : 1966				*
57	IS/IEC	Environmental testing Part 2 Tests		-	Identical under single
	60068-2-20):2021	Section 20 Tests Ta and Tb: Test			numbering
	IEC 60068-2-20:	methods for solderability and			
	2021 IEC 60068-2-20:	resistance to soldering heat of devices with leads			
	2021	devices with leads			
58	IS/IEC	Environmental Testing Part 2:			Identical under single
] 36	60068-2-21):2021	Tests Section 21: Test U:		_	numbering
	IEC	Robustness of Terminations and			numbering
	60068-2-21:2021	Integral Mounting Devices			
	IEC	Superseding IS 9000 Part			
	60068-2-21:2021	19Section 1 to 5:1986			
59	IS/IEC	Environmental testing Part 2 Tests		-	
	60068-2-58):2015	Section 58 Test Td: Test methods			
	IEC 60068-2-58:	for solderability resistance to			
	2015	dissolution of metallization and to			
		soldering heat of surface mounting			
		devicesSMD			
60	IS/IEC	Environmental testing Part 2 Tests		-	Identical under single
	60068-2-69):2017	Section 69 Test TeTc: Solderability			numbering
	IEC 60068-2-69:	testing of electronic components			
	201	and printed boards by the wetting			
	IEC 60068-2-69:	balance force measurement method			
<u></u>	201	Englishman and Landing B. (2 F.)			
61	IS/IEC	Environmental testing Part 2 Tests		-	
	60068-2-82):2019	Section 82 Test Xw1: Whisker test			
	IEC 60068-2-82: 2019	methods for components and parts used in electronic assemblies			
	2019	used in electronic assemblies			
62	IS/IEC	Environmental testing Part 2 Tests		_	Identical under single
	60068-2-83):2011	Section 83 Test Tf: Solderability			numbering
	IEC 60068-2-83:	testing of electronic components			
	2011	for surface mounting devices SMD			
	IEC 60068-2-83:	by the wetting balance method			
	2011	using solder paste			
63	IS/IEC	Fixed resistors for use in electronic		-	Identical under single
	60115-1:2020	equipment Part 1 Generic			numbering
	IEC 60115-1: 2020	specification			
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1	IEC 60115-1: 2020			I	1
64		Fixed resistors for use in electronic		-	Identical under single
	60115-2:2023	equipment Part 2 Sectional			numbering
	IEC 60115-2: 2023	specification: Low-power film			
	IEC 60115-2: 2023	resistors with leads for through-			
		hole assembly on circuit boards			
		(THT)			
65		Printed Board Design Manufacture	March, 2021	-	Identical under dual
	IEC 60194 : 2015	and Assembly-Terms and			numbering
	Reviewed In: 2021	Definitions			
	IEC 60194 : 2015				*1 . 1 1 1 1
66		Method of measurement of current		-	Identical under single
	IEC 60195:2016	noise generated in fixed resistors			numbering
(7	IEC 60195:2016	Superseding IS 5027 : 1969			Identical under ainele
67	IS/IEC 60384-4:2016	Fixed capacitors for use in		-	Identical under single
	IEC 60384-4: 2016	electronic equipment Part 4 Sectional specification Fixed			numbering
	IEC 60384-4: 2016	aluminium electrolytic capacitors			
	IEC 00364-4, 2010	with solid MnO2 and non-solid			
		electrolyte Superseding IS 4317:			
		1983 and ISQC 300300 : 1992			
68	IS/IEC	Fixed capacitors for use in		_	Identical under single
	60384-9:2015	electronic equipment Part 9:			numbering
	IEC 60384-9: 2015	Sectional specification: Fixed			namoening
	IEC 60384-9: 2015	capacitors of ceramic dielectric			
	120 00301 7. 2013	Class 2 Superseding IS 2786 Part			
		1: 1978 and ISQC 300700: 1994			
69	IS/IEC	Fixed capacitors for use in		-	Identical under single
	60384-15:2017	electronic equipment Part 15			numbering
	IEC 60384-15: 2017				
	IEC 60384-15: 2017	tantalum capacitors with non-solid			
		or solid electrolyte			
70	IS/IEC	Fixed capacitors for use in		-	Identical under single
	60384-141-1):2016	electronic equipment Part 14 Blank			numbering
	IEC 60384-14-1:	detail specification Fixed			
	2016	capacitors for electromagnetic			
	IEC 60384-14-1:	interference suppression and			
	2016	connection to the supply mains			
		Section 1 Assessment level DZ			
<u> </u>		Superseding ISQC 302401 : 1994			
71	IS/IEC 60440:2012	Method of measurement of non-		-	Identical under single
	IEC 60440 : 2012	linearity in resistors			numbering
70	IEC 60440 : 2012	Tack models de ferri 1 / 1 1			Idanelication 1: 1
72	IS/IEC	Test methods for electrical materials interconnection structures		-	Identical under single
	61189-1:2001 IEC 61189-1: 2001	and assemblies Part 1 General test			numbering
	IEC 61189-1: 2001				
73	IS/IEC 61189-1; 2001	methods and methodology Test methods for electrical		_	Identical under single
'3	61189-2:2006	materials printed boards and other		_	numbering
	IEC 61189-2:2006	interconnection structures and			I I I I I I I I I I I I I I I I I I I
		assemblies Part 2:Test methods for			
		materials for interconnection			
		structures			
74	IS/IEC	Test methods for electrical		-	Identical under single
	61189-3:2007	materials printed boards and other			numbering
	IEC 61189-3: 2007	interconnection structures and			
		assemblies Part 3 Test methods for			
		interconnection structures printed			
		boards			
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	1			1	1
75	IS/IEC	Test methods for electrical		-	Identical under single
		materials interconnection structures			numbering
		and assemblies Part 5 Test methods			
	IEC 61189-5:2006	for printed board assemblies			
76	IS/IEC	Electronics assembly technology		-	Identical under single
	62137-4:2014	Part 4 Endurance test methods for			numbering
	62137-4: 2014	solder joint of area array type			
<u> </u>	62137-4: 2014	package surface mount devices			
77	IS/IEC	Printed Boards Part 1 Generic	March, 2024	-	Identical under dual
	62326-1:2002	specification			numbering
	IEC 62326-1 : 2002				
	Reviewed In: 2024				
78	IEC 62326-1 : 2002 IS/IEC	Printed Boards Part 20 Printed	Manah 2024		Identical under dual
/8	62326-20:2016		March, 2024	-	
	IEC 62326-20:2016	Circuit Boards for High-Brightness LEDs			numbering
	Reviewed In : 2024	LEDS			
	IEC 62326-20:				
	2016				
79		Electronics Assembly Technology-	March, 2024	_	Identical under dual
'9	IEC 62421 : 2007	Electronic Modules	1V1d1C11, 2U24]	numbering
	Reviewed In : 2024	Electronic Wodules			numbering
	IEC 62421 : 2007				
80	IS/IEC/TR	Study for the derating curve of		_	Identical under single
80	63091:2017	surface mount fixed resistors		_	numbering
		Derating curves based on terminal			numbering
	IEC TR 63091:	part temperature			
	2017	part temperature			
81	IS 7305:2018	Fixed capacitors for use in	March, 2021	_	Identical under dual
	IEC 60384-1 : 2016	=	1141411, 2021		numbering
	Reviewed In: 2021	specification (Second Revision)			namoering
	IEC 60384-1:2016				
82		Semiconductor devices - Integrated	March, 2021	-	Identical under single
	~	circuits - Generic specification for	, .		numbering
		film integrated circuits and hybrid			
	taken up for revision	_			
	IECQC 760000				
83	IS/QC 760100:1995	Semiconductor devices - Integrated	March, 2021	-	Identical under single
	Reviewed In: 2021	circuits - Sectional specification			numbering
	Reaffirmed but not	for film integrated circuits and			
	taken up for revision	hybrid film integrated circuits on			
	IECQC 760100	the basis of qualification approval			
		procedure			
84	_	Semiconductor devices - Integrated	March, 2021	-	Identical under single
		circuits - Blank detail specification			numbering
	Reaffirmed but not	for film integrated circuits and			
		hybrid film integrated circuits on			
	IECQC 760101	the basis of qualification approval			
<u></u>		procedure			
85	_	Semiconductor devices - Integrated	March, 2021	-	Identical under single
	Reviewed In: 2021	circuits - SectlOnal specification			numbering
	Reaffirmed but not	for film integrated circuits and			
	taken up for revision				
	IECQC 760200	the basis of the capability approval			
-	10/00/2000/11005	procedures	M 1 2021		T1 .' 1 1 ' 1
86		Semiconductor devices - Integrated	March, 2021	-	Identical under single
		circuits - Blank detail specification			numbering
	Reaffirmed but not	for film integrated circuits and			
	laken up for revision	hybrid film integrated circuits on			

	IECQC 760201	the basis of the capability approval procedures			
87	IS/OC 790130·1995	Semiconductor devices - Integrated	March, 2021	-	Identical under single
	_	circuits - Digital integrated circuits			numbering
	Reaffirmed but not	- Blank detail specification for			namoernig
		HCMOS digital integrated circuits			
	IECQC 790130	(Series 54/74 HC, 54/74 HCT,			
		54/74 HCU)			
88	~	Semiconductor devices - Integrated	March, 2021	-	Identical under single
		circuits - Digital integrated circuits			numbering
	Reaffirmed but not	- Blank detail specification for			
	taken up for revision				
	IECQC 790131	integrated circuits (Series 4000			
		Band 4000 Ub)			
89		Semiconductor devices - Integrated	March, 2021	-	Identical under single
		circuits - Digital integrated circuits			numbering
	Reaffirmed but not	- Blank detail specification for			
	taken up for revision				
	IECQC 790132	integrated circuit gates (Excluding			
		Uncommitted Logic Arrays)			
90		Semiconductor devices - Integrated	March, 2021	-	Identical under single
	Reviewed In: 2021	circuits - Analogue integrated			numbering
	Reaffirmed but not	circuits blank detail specification			
	taken up for revision	_			
	IECQC 790202	operational amplifiers			
91	IS 8186:2020	Marking Codes for Resistors and	-	-	Identical under dual
	IEC 60062 : 2016	Capacitors (First Revision)			numbering
	IEC 60062 : 2016				
92	IS 824:2021	Preferred number series for		-	Identical under dual
	IEC 60063: 2015	Resistors and Capacitors			numbering
	IEC 60063: 2015				
93	IS 8872 (Part	Potentiometers for use in	November, 2021	-	Identical under dual
	1):2018	electronic equipment: Part 1			numbering
	IEC 60393-1:2008	generic specification (First			
	Reviewed In: 2021	Revision)			
	IEC 60393-1:2008				
94	IS 9000 (Part 19/Sec	Basic environmental testing	October, 2022	-	Indigenous
	15):1986	procedures for electronic and			
	Reviewed In: 2022	electrical items: Part 19 test u:			
		robustness of terminations and			
		integral mounting devices (First			
		Revision)			
95	IS 9256 (Part	Fixed capacitors for use in	May, 2022	-	Identical under dual
	1):2019	electronic equipment: Part 1			numbering
	IEC 60384-2 : 2011	Sectional specification - Fixed			
	Reviewed In: 2022	metallized polyethylene			
	IEC 60384-2 :2011	terephthalate film dielectric d.c.			
		capacitors (First Revision)			
96	IS 9638 (Part	Specification for fixed polyester	December, 2021	-	Indigenous
	1):1980	film dielectric capacitors for direct	,		
	Reviewed In: 2021	current: Part 1 general			
		requirements and methods of tests			
ь	1	1 1		1	

Standards under Development

		Projects Approved		
SI. No.	SI. No. Doc No. Title			

No Records Found

		Preliminary Draft Standards	
SI. No.	SI. No. Doc No. Title		
No Records Found			

	Drafts Standards in WC Stage				
SI. No.	SI. No. Doc No. Title				
1	LITD 5 (25416)	Varistors for use in Electronic Equipment Part 1 Generic Specification			
2	LITD 5 (25417)	Fixed Capacitors for use in Electronic Equipment Part 11 Sectional Specification Fixed			
		Polyethylene-Terephthalate Film Dielectric Metal Foil DC Capacitors			
3	LITD 5 (25418)	Fixed Capacitors for use in Electronic Equipment Part 8 Sectional Specification Fixed Capacitors			
		of Ceramic Dielectric Class 1			
4	LITD 5 (25420)	Fixed Capacitors for use in Electronic Equipment Part 3 Sectional Specification Surface Mount			
		Fixed Tantalum Electrolytic Capacitors with Solid MnO2 Electrolyte			

	Draft Standards Completed WC Stage		
SI. No.	Doc No.	Title	
1	LITD 5 (23273)	Semiconductor Devices Discrete Devices Part 7 Bipolar Transistors First Revision Amendment - 1	

		Finalized Draft Indian Standard
SI. No.	Doc No.	Title
1	LITD 5 (23252)	Fixed resistors for use in electronic equipment Part 2 Blank detail specification Section 10 Low-
		power film resistors with leads for through-hole assembly on circuit boards THT for general
		electronic equipment classification level G
2	LITD 5 (23253)	Fixed resistors for use in electronic equipment Part 4 Sectional specification Power resistors for
		through hole assembly on circuit boards THT or for assembly on chassis Superseding ISQC 400200
		1992
3	LITD 5 (23254)	Fixed Capacitors for use in Electronic Equipment Part 1 Generic Specification
4	LITD 5 (23255)	Fixed Capacitors for use in Electronic Equipment Part 1 Generic Specification Section 1 Blank
		Detail Specification
5	LITD 5 (23256)	Fixed Capacitors for use in Electronic Equipment Part 2 Sectional Specification - Fixed
		Metallized Polyethylene Terephthalate Film Dielectric DC Capacitors
6	LITD 5 (23257)	Fixed Capacitors for use in Electronic Equipment Part 14 Sectional Specification - Fixed
		Capacitors for Electromagnetic Interference Suppression and Connection to the Supply Mains
		Superseding ISQC 302400 1994
7	LITD 5 (23258)	Thermistors Directly heated positive temperature coefficient Part 1 Generic specification
8	LITD 5 (23274)	Semiconductor Devices Discrete Devices Part 8 Field-Effect Transistors Second Revision
		Amendment - 1

		Finalized Draft Indian Standards under Print
SI. No.	Doc No.	Title
No Records Found		

Total Published Standards:93 Total Standards Under development:13

Aspect Wise Report

Product: 64 Code of Practices: 9 Methods of Test: 17 Terminology: 3 Dimensions: 1 System Standard: 0 Safety Standard: 0 Others: 0

Service Specification : 0 Process Specification : 0 Unclassified : 2

Annexure-I :List of Indian Standards Withdrawn/Superseded

SI. No.	IS No. & Year	Title
1	IS 10249 (Part 2/Sec	Specification for voltage dependent resistors Varistors Part 2 low voltage Sec 1 type VDF 1
	1):1983	
	Reviewed In: 2021	
2	IS 10249 (Part 2/Sec	Specification - for voltage dependent resistors Varistors Part 2 low voltage Sec 2 type VDS 1
	2):1983	
	Reviewed In: 2021	
3	IS 1031:1967	Methods of measurements on loudspeakers and loudspeaker systems
4	IS 1032:1957	General requirements end tests for pressure unit operated horn loudspeaker systems
	YG 10220 1002	
5	IS 10320:1982	General requirements and tests for axial lead cores made of magnetic oxides or iron powder
	IEC 60701	
	Reviewed In: 2008	
6	IS 1033:1957	General requirement and tests for direct radiator moving coil loudspeaker
7	IS 1034:1957	Loudspeakers systems for community radio receivers
	15 155 1175 /	Zodasposito ojotenio tet community funto receivero
8	IS 10424:1982	Guide for design and use of printed boards
	Reviewed In: 2020 IEC	
	60326-3:	
9	IS 10477:1982	Environmental testing procedures for microcircuits
	Reviewed In: 2023	
10	IS 10825 (Part 1):1975	Specification for ceramic dielectric capacitors type 1 Part 1 general requirements and methods of
	Reviewed In: 2021	tests
11	IS 10825 (Part 2):1984	Specification for ceramic dielectric capacitors type 1 Part 2 type FCCT - 1
	Reviewed In: 2021	
12	IS 10825 (Part 3):1984	Specification for ceramic capacitors type 1 Part 3 FCCT 2
	Reviewed In: 2021	
13	IS 10991 (Part 1):1984	Specification for fixed metallized polypropylene film dielectric capacitors Part 1 general
	Reviewed In: 2021	requirements and methods of tests
14	IS 11214:1984	Guide for repair of printed wiring boards and assemblies
<u> </u>	Reviewed In: 2020	
15	IS 11392 (Part 1/Sec	Dimensions of mounting accessories of pot cores for printed circuit board mountings Part 1 - For
	1):1985	pot cores of size 18 x 11 Mm Sec 1 type 1
16	Reviewed In : 2023	Constitution for Continue III and an activities described and activities and the continue III and activities and activities and activities and activities and activities and a
16	IS 11515 (Part 1):1985	Specification for fixed metallized polycarbonate film dielectric capacitors Part 1 general
17	Reviewed In : 2018 IS 11515 (Part 2):1986	requirements and methods of tests Specification for fixed metallised polycarbonate film dielectric capacitors Part 2 type FCCM 1
1 /	Reviewed In : 2018	Specification for fixed metamised polycarbonate finit dielectric capacitors Part 2 type FCCM 1
18	IS 11515 (Part 3):1986	Specification for fixed metallised polycarbonate film dielectric capacitors Part 3 type FCCM 2
10	Reviewed In : 2018	Specification for fixed inetainsed polycarbonate finit dielectric capacitors Fart 5 type FCCN 2
19	IS 12032 (Part 5):1993	Graphical symbols for diagrams in the field of electrotechnology Part 5 semiconductors and
19	IEC 617-5: 1983	electron tubes
	Reviewed In : 2018 IEC	Ciccion tubes
	617-5: 1983	
20	IS 12032 (Part 12):1994	Graphical symbols for diagrams in the field of electrotechnology Part 12 binary logic elements
	IEC 617-12: 1983	oraphical symbols for diagrams in the field of electrocenhology fart 12 binary logic elements
	Reviewed In : 2018 IEC	
I	Teviewed in . 2016 ILC	ı

	617-12: 1983	1
21	IS 12032 (Part 13):1992	Graphical symbols for diagrams in the field of electrotechnology Part 13 analogue elements
	IEC 617-13: 1978	
	Reviewed In: 2018 IEC	
	617-13: 1978	
22	IS 12071:1987	Guide for assembly of printed boards
	Reviewed In: 2017	Canada and Araba
23	IS 12284:1988	Specification for prepreg for ruse in multilayer printed boards
	Reviewed In : 2020 IEC	property pro
	60249-3-1: 1981	
24	IS 12641:2004	Semiconductor devices - Mechanical and climatic test methods First Revision
2.	IEC 60749: 2002	Someonactor devices international and communic test methods in the revision
	Reviewed In: 2018 IEC	
	60749: 2002	
25	IS 12970 (Part 2/Sec	Semiconductor devices integrated circuits Part 2 digital integrated circuits - Essential ratings and
23	2):1992	characteristics Sec 2 integrated circuit memories
	Reviewed In: 2018	characteristics See 2 integrated effectit memories
26	IS 12970 (Part 2/Sec	Semiconductordevices - Integrated circuits Part 2 digital integrated circuits - Essential rating and
20	3):1993	characteristics Sec 3 integrated circuit microprocessors
	Reviewed In : 2018	characteristics see 3 integrated effects filteroprocessors
27	IS 12970 (Part 3/Sec	Semiconductor devices - Integrated circuits Part 3 digital integrated circuits - Measuring methods
21	1):1992	Sec 1 general
	Reviewed In : 2018	Sec 1 general
20		Cambon director devices interpreted circuits Dant 2 digital interpreted circuits. Measuring mothods
28	IS 12970 (Part 3/Sec	Semkonductor devices integrated circuits Part 3 digital integrated circuits - Measuring methods
	2):1992	Sec 2 static characteristics
20	Reviewed In : 2018	Control of the Late of the Transport of the North Port 2 divided by the Late of the Manufacture of the Late
29	IS 12970 (Part 3/Sec	Semiconductor devices - Integrated circuits Part 3 digital integrated circuits - Measuring methods
	3):1993	Sec 3 dynamic measurements
20	Reviewed In : 2018	Control of the late of the late of the late of the Dord Control of the late of the
30	IS 12970 (Part 5/Sec	Semiconductor devices integrated circuits Part 5 analogue integrated circuits - Essential ratings
	2):1992	and characteristics Sec 2 operational amplifiers
31	Reviewed In: 2018 IS 12970 (Part 5/Sec	Semiconductor devices - Integrated circuits Part 5 analogue integrated circuits - Essential ratings
31	3):1992	and characteristics Sec 3 audio amplifiers video amplifiers and multichannel amplifiers for
	Reviewed In : 2018	telecommunications
32	IS 12970 (Part 5/Sec	Semiconductor devices - Integrate d circuits Part 5 analogue integrated circuits - essential ratings
32	4):1992	and characteristics Sec 4 R F and I F amplifiers
	4).1992 Reviewed In : 2018	and characteristics Sec 4 K F and 1 F amplifiers
33	IS 12970 (Part 5/Sec	Semiconductor devices - Integrated circuits Part 5 analogue integrated circuits - Essential ratings
33	5):1993	and characteristics Sec 5 voltage and current regulators
	Reviewed In : 2018	and characteristics Sec 3 voltage and current regulators
34	IS 12970 (Part 5/Sec	Semiconductordevices - Integrated circuits Part 5 analogue lNtegrated circuits - Essential ratings
34	6):1993	and characteristics Sec 6 analogue signal switching circuits
	Reviewed In : 2018	and characteristics see o analogue signal switching circuits
35	IS 12970 (Part 6/Sec	Semiconductor devices - Integrated circuits Part 6 analogue integrated circuits measuring methods
33	1):1992	Sent 1 general
	Reviewed In : 2018	Sec 1 general
36	IS 12970 (Part 6/Sec	Semiconductor devices - Integrated circuits Part 6 analogue integrated circuits measuring methods
30	2):1992	Sec 2 linear amplifiers
	*	Sec 2 inical amplifiers
37	Reviewed In: 2018 IS 12970 (Part 6/Sec	SemicOnductor devices integrated circuits Part 6 analogue integrated circuits measuring methods
31	3):1992	Sec 3 voltage regulators
	1	Sec 5 voltage regulators
38	Reviewed In: 2018 IS 12970 (Part 6/Sec	Semiconductor devices - Integrated circuits Part 6 analogue integrated circuits - Measuring
30	4):1992	methods Sec 4 analogue signal switching circuits
	*	methods see 4 analogue signal switching chedits
39	Reviewed In : 2018	Code of safety requirements for electronic mains operated sudic applificus income and in IC
39	IS 1301:1958	Code of safety requirements for electronic mains-operated audio amplifiers incorporated in IS
40	IC 1202.1050	616 Methods of measurements on cudio amplificate incomparated in IS 0202 Port 2
40	IS 1302:1958	Methods of measurements on audio amplifiers incorporated in IS 9302 Part 2

	I	
41	IS 13342:2001	Magnetic Oxide Cores ETD - Cores Intended for use in Power Supply Applications - Dimensions
	ISO 1185	
	Reviewed In: 2008	
42	IS 13504:1992	Method of measurement of non - Linearity in resistors
	Reviewed In: 2020 IEC	
	60440: 1973	
43	IS 13669:1993	Permanent polymer coating materials solder-resist for use in the manufacture of printed circuits
	IEC 249-3-3	
	Reviewed In: 2008	
44	IS 1490:1959	Recommendations for minimum performance requirements of mains-operated public address amplifiers incorporated in IS 10426
45	IS 14901 (Part 4):2016 IEC 60747-4	Semiconductor Devices Discrete Devices Part 4 Microwave Diodes and Transistors
	ILC 00/4/-4	
46	IS 14901 (Part 5/Sec	Semiconductor Devices - Discrete Devices and Integrated Circuits Part 5 Optoelectronic Devices
40	1):2010	Secton 1 General
	IEC 60747-5: 2002	Section 1 Constan
	Reviewed In: 2014 IEC	
	60747-5: 2002	
47	IS 14924:2001	Synthetic Quartz Crystal s and Guide to the Use
	IEC 758	
	Reviewed In: 2008	
48	IS 15212:2002	Specification and Characterization Methods for Nonwoven E Glass Mat
	IEC/PAS 62212	
	Reviewed In: 2008	
49	IS 15213:2002	Specification and Characterization Methods for Nonwoven Para-Aramid Reinforcement
	IEC/PAS 62213	
	Reviewed In: 2008	
50	IS 15214:2002	Generic Requirements for Implementation of Product Manufacturing Description Data and
	IEC/PAS 62119	Transfer Methodology
	Reviewed In: 2008	
51	IS 15215:2002	Performance Guide Manual for Single- and Double-Sided Flexible Printed Wiring Boards
	IEC/PAS 62123	
	Reviewed In: 2008	
52	IS 15252:2002	Generic Performance Printed Boards
	IEC/PAS 62214	
	Reviewed In: 2008	
53	IS 15479:2004	Qualification and performance specification for high density interconnect HDI layers or boards
	IEC/PAS 62293	
	Reviewed In:	
	2019 IEC/PAS 62293	
54	IS 1819:1961	Recommendations for general requirements of public address amplifiers
55	IS 1885 (Part 6):1978	Electrotechnical vocabulary Part 6 printed circuits First Revision
	Reviewed In: 2014 IEC	
	60194	
56	IS 1885 (Part 7):2001	Electrotechnical vocabulary Part 7 semiconductor devices and integrated circuits Second Revision
	Reviewed In: 2017 IEC	
	60050-521	
57	IS 1885 (Part 45):1977	Electrotechnical vocabulary Part 45 capacitors
	Reviewed In: 2023 IEC	
	60050-516	
58	IS 1885 (Part 46):1977	Electrotechnical vocabulary Part 46 resistors
	Reviewed In: 2023 IEC	
	60050-516	
59	IS 2001:1968	Specification for fixed silvered mica capacitors First Revision
	Reviewed In: 2018	
	IS 2032 (Part 8):1965	Graphical symbols used in electrotechnology Part 8 semiconductor devices

I	Reviewed In: 2023	
61	IS 2032 (Part 17):1975	Graphical symbols used in electrotechnology Part 17 Ferrite cores and magnetic storage matrices
	Reviewed In: 2011	
62	IS 2032 (Part 24):1980	Graphical symbols used in electrotechnology Part 24 Binary logic elements
	IEC 117-13	
	Reviewed In: 2011	
63	IS 2748:1964	Methods of measurements on microphones
64	IS 2786 (Part 1):1978	Specification for ceramic dielectric capacitors type 2 Part 1 general requirements and methods of
	Reviewed In: 2021	test First Revision
65	IS 2786 (Part 2):1984	Specification for ceramic dielectric capacitors type 2 Part 2 FCCG 01 and FCCG 02 capacitors
	Reviewed In: 2023	
66	IS/QC 300200:2000	Fixed capacitors for use in electronic equipment Part 15 sectional specification fixedtantalum
	Reviewed In: 2021 IECQC	capacitors with non - Solid or solid electrolyte
	300200: 1982	
67	IS/QC 300300:1992	Fixed capacitors for use in electronic equipment Sectional specification aluminium electrolytic
	Reviewed In: 2021 IECQC	capacitors with solid and non - Solid elecrolyte
(0)	300300: 1985	Find and the Control of the American Control of the
68	IS/QC 300400:1988 Reviewed In : 2018 IECQC	Fixed capacitors for use in electronic equipment Sectional specification fixed metallized polyethylene Terephthalate film dielectric DC capacitors
	300400: 1982	polyethylene Terephinalate Thin dielectric De capacitois
69	IS/QC 300700:1994	Fixed capacitors for use in electronic equipment Sectional specification for fixed capacitors of
	Reviewed In: 2018 IECQC	ceramic dielectric class 2
	300700: 1988	
70	IS/QC 302401:1994	Fixed capacitors for use in electronic equipment blank detail specification for fixed capacitors for
	Reviewed In: 2018 IECQC	electromagnetic interference suppression and connection to the supply mains assessment level D
	302401: 1993	
71	IS 3641:1976	Methods of measurements on hearing aids
72	IS 3671 (Part 1):1980	Specification for air dielectric variable tuning capacitors Part 1 tests and general requirements
, -	Reviewed In: 2018	First Revision
73	IS 3700 (Part 7):1970	Essential ratings and characteristics of semiconductor devices Part 7 reverse blocking triode
	Reviewed In: 2023 IEC	thyristors
	60147-1	
74	IS 3715 (Part 4):1971	Letter symbols for semiconductor devices Part 4 thyristors First Revision
	Reviewed In: 2018 IEC	
75	60148: 1969 IS 3723 (Part 1):1978	Specification for capacitors for radio interference suppression Part 1 general requirements and
13	Reviewed In : 2021	methods of tests First Revision
76	IS 3723 (Part 2):1983	Specification for capacitors for radio interference suppression Part 2 type Fcrs 1
	Reviewed In: 2021	Specification output to the first the second output of the second of the second output of the
77	IS 3723 (Part 3):1983	Specification for capacitors for radio interference suppression Part 3 type Fcrs 2
	Reviewed In: 2021	
78	IS/QC 390000:1994	Fixed film resistor networks for use in electronic equipment - Generic specification
	Reviewed In: 2018 IECQC	
	390000: 1991	
79	IS/QC 390100:1993	Fixed film resistor networks for use in electronic equipment Secal specification for film
	Reviewed In: 2018 IECQC	resistornetworksofassessedquality on the basis of the capability approval procedure
00		Fixed film register naturally for use in electronic annium and black days in electronic for the
80	-	
	_	
81		
		9779
82	IS 3932:1966	Sound level meters for general purpose use incorporated in IS 9779
83	IS/QC 400000:1988	Fixed resistors for use in electronic equipment generic specification
	Reviewed In: 2018 IECQC	
	400000: 1982	
	390100: 1991 IS/QC 390101:1993 Reviewed In : 2018 IECQC 390101: 1991 IS 3931:1966 IS 3932:1966 IS/QC 400000:1988 Reviewed In : 2018 IECQC	Fixed film resistor networks for use in electronic equipment blank detail specification for resistor networks of assessed quality on the basis of the capABility approval procedure. Assessment level e Sound level meters for the measurement of noise emitted by motor vehicles incorporated 9779 Sound level meters for general purpose use incorporated in IS 9779

0.4	XG10.G 100000 1000	
84	IS/QC 400300:1992	Fixed resistors for use in electronic equipment Sectional specification fixed precision resistors
	Reviewed In: 2021 IECQC	
	400300: 1982	
85	IS/QC 400301:1992	Fixed resistors for use in electronic equipment blank detail specification fixed precision resistors
	Reviewed In: 2021 IECQC	assessment level E
	400301: 1983	
86	IS/QC 400402:1993	Fixed resistors for use inelectronic equipment - Blank detail specification - Fixed resistor networks
	Reviewed In: 2018 IECQC	with individually measurable resistors of either different resistance values or different rated
	400402: 1983	dissipations assessment level E
07	IS/QC 410000:2000	*
87	_	Potentiometers for use in electronic equipment Part 1 generic specification Sec 1 Scope
	Reviewed In: 2018 IECQC	
	410000: 1989	
88	IS/QC 420101:1994	Varistors for use in electronic equipment - Blank detail specification for silicon carbide surge
	Reviewed In: 2018 IECQC	suppression varistors assessment level E
	420101	
89	IS 4317:1983	Specification for aluminium electrolytic capacitors with non - Solid electrolyte Second Revision
-	Reviewed In: 2021 IEC	
	60384-4	
00		Mahada Carana and Andrew Later Day 7
90	IS 4400 (Part 7):1971	Methods of measurements on semiconductor devices Part 7 reverse blocking triode thyristors
	Reviewed In: 2018 IEC	
	60147-2: 1963	
91	IS 4406:1967	General Requirements For Hearing Aids
92	IS 4411:1967	Code for designation of semiconductor devices
	Reviewed In: 2021	
93	IS 4482:1967	Hearing Aids
	15 1102.1507	Treating That
94	IS 4633:1968	Fixed Metallized-paper Dielectric Capacitor for Direct Current
94		Fixed Metallized-paper Dielectric Capacitor for Direct Current
	Reviewed In: 2015	
95	IS 5000 (Part 1):1969	Dimensions of semiconductor devices Devices outline OD 1
	Reviewed In: 2008	
96	IS 5000 (Part 4):1969	Dimensions of semiconductor devices Device outline OD 4
	Reviewed In: 2008	
97	IS 5000 (Part 5):1969	Dimensions of semiconductor devices Device outline OD 5
	Reviewed In: 2008	
98	IS 5000 (Part 6):1969	Dimensions of Semiconductor Devices Device Outline OD6
70	Reviewed In: 2008	Difficusions of Schileonductor Devices Device Outline ODo
00		Discosion of Consistent at a Desire Desire Ordina ODZ
99	IS 5000 (Part 7):1969	Dimensions of Semiconductor Devices Device Outline OD7
	Reviewed In: 2008	
100	IS 5000 (Part 8):1969	Dimensions of Semiconductor Devices - Device Outline OD8
	Reviewed In: 2008	
101	IS 5000 (Part 9):1986	Dimensions of semiconductor devices Device outline OD 9
	Reviewed In: 2008	
102	IS 5000 (Part 10):1971	Dimensions of Semiconductor Devices Device Outline OD10
	Reviewed In: 2008	
103	IS 5000 (Part 11):1971	Dimensions of Semiconductor Devices Device Outline OD11
103		Difficultions of Schildonauctor Devices Device Outline OD11
101	Reviewed In : 2008	
104	IS 5000 (Part 12):1971	Dimensions of semiconductor devices Device outline OD 12
	Reviewed In: 2008	
105	IS 5000 (Part 13):1971	Dimensions of semiconductor devices Device outline OD 13
	Reviewed In: 2008	
106	IS 5000 (Part 14):1971	Dimensions of Semiconductor Devices Device Outline OD14
	Reviewed In: 2008	
107	IS 5000 (Part 15):1973	Dimensions of semiconductor devices Device outline OD 15
107	Reviewed In : 2008	Difficultions of semiconductor devices bevice outline OD 13
100		Dimensions of Coming duster Devices Device On the ODIC
108	IS 5000 (Part 16):1973	Dimensions of Semiconductor Devices Device Outline OD16
1	Reviewed In: 2008	
_		
109	IS 5000 (Part 17):1974 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 17

110	70 5000 (D 10) 1051	
110	IS 5000 (Part 18):1974	Dimensions of Semiconductor Devices Device Outline OD18
111	Reviewed In : 2008	D' ' (G ' 1 (D ' D ' OD10
111	IS 5000 (Part 19):1974	Dimensions of Semiconductor Devices Device Outline OD19
110	Reviewed In : 2008	
112	IS 5000 (Part 20):1978	Dimensions of Semiconductor Devices Device Outline OD 20
	Reviewed In: 2008	
113	IS 5000 (Part 21):1979	Dimensions of Semiconductor Device Outline OD 21
	Reviewed In: 2008	
114	IS 5000 (Part 23):1978	Dimensions of semiconductor devices Device outline OD 23
	Reviewed In: 2008	
115	IS 5000 (Part 25):1978	Dimensions of semiconductor devices Device outline OD 25
	Reviewed In: 2008	
116	IS 5000 (Part 26):1978	Dimensions of semiconductor devices Device outline OD 26
	Reviewed In: 2008	
117	IS 5000 (Part 27):1978	Dimensions of Semiconductor Device Outline OD 27
	Reviewed In: 2008	
118	IS 5000 (Part 28):1978	Dimensions of Semiconductor Devices Device Outline OD 28
	Reviewed In: 2008	
119	IS 5000 (Part 29):1979	Dimensions of semiconductor devices Device outline OD 29
	Reviewed In: 2008	
120	IS 5000 (Part 31):1981	Dimensions of Semiconductor Devices Device Outline OD31
	Reviewed In: 2008	
121	IS 5000 (Part 32):1981	Dimensions of semiconductor devices Device outline OD 32
	Reviewed In: 2008	
122	IS 5000 (Part 33):1981	Dimensions of semiconductor devices Device outline OD 33
122	Reviewed In : 2008	Difficultions of semiconductor devices bevice outline ob 33
123	IS 5000 (Part 34):1981	Dimensions of Semiconductor Devices Device Outline OD34
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750111 181 IS 7741 (Part 1):1975 Loudspeakers Part 1 - General requirements and tests 182 IS 7741 (Part 4):1977 loudspeakers Part 4 Loudspeakers for community radio receivers Reviewed In: 1993 183 IS 7748 (Part 1):1975 Specification for variable capacitors Part 1 tests and general requirements Reviewed In: 2018 184 IS 8083:1976 Dimensions of ceramic dielectric capacitors of the plate type Reviewed In: 2015 185 IS 8238:1976 Guide for use of variable capacitors in electronic equipment	100		
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IS 7741 (Part 4):1977 loudspeakers Part 4 Loudspeakers for community radio receivers Reviewed In: 1993 IS 7748 (Part 1):1975 Specification for variable capacitors Part 1 tests and general requirements Reviewed In: 2018 IS 8083:1976 Dimensions of ceramic dielectric capacitors of the plate type Reviewed In: 2015 IS 8238:1976 Guide for use of variable capacitors in electronic equipment	101		Loudspeakers 1 art 1 - General requirements and tests
Reviewed In: 1993 IS 7748 (Part 1):1975 Reviewed In: 2018 IS 8083:1976 Reviewed In: 2015 IS 8238:1976 Guide for use of variable capacitors in electronic equipment		IEC 208-3	
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IS 7748 (Part 1):1975 Reviewed In : 2018 IS 8083:1976 Reviewed In : 2015 IS 8238:1976 Guide for use of variable capacitors Part 1 tests and general requirements dielectric capacitors of the plate type Reviewed In : 2015 Guide for use of variable capacitors in electronic equipment	102	` '	Toucospeakers I are a Louispeakers for community fauto receivers
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184 IS 8083:1976 Dimensions of ceramic dielectric capacitors of the plate type Reviewed In: 2015 185 IS 8238:1976 Guide for use of variable capacitors in electronic equipment	103		Specification for variable capacitors fart facts and general requirements
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185 IS 8238:1976 Guide for use of variable capacitors in electronic equipment	104		Difficusions of ceramic diefectife capacitors of the plate type
	195		Guide for use of variable canacitors in electronic equipment
Reviewed III. 2013	103		Outdo for use of variable capacitors in electronic equipment
		Reviewed III . 2013	

106	XC 0.42 < 2001	Walley Barrier Committee and C
186	IS 8426:2001	Measuring Methods for Properties of Gyromagnetic Materials Intended for Application at
	IEC 60556	Microwave Frequencies
10-	Reviewed In: 2008	
187	IS 8507 (Part 1):1977	Specification for fixed tantalum capacitors with solid electrolyte Part 1 general requirements and
100	Reviewed In: 2021	methods of tests
188	IS 8507 (Part 2/Sec 1):1981	Specification for fixed insulated hermetically sealed tantalum capacitors with solid electrolyte Part
	Reviewed In: 2023	2 type FCST 1 Sec 1 polar
189	IS 8507 (Part 2/Sec 2):1982	Specification for fixed insulated hermetically sealed tantalum capacitors with solid electrolyte Part
	Reviewed In: 2023	2 type FCST 1 Sec 2 non - Polar
190	IS 8507 (Part 3/Sec 1):1981	Specification for fixed insulated hermetically sealed tantalum capacitors with solid electrolyte Part
	Reviewed In: 2023	3 type fcst 2 Sec 1 polar
191	IS 8507 (Part 3/Sec 2):1982	Specification for fixed insulated hermetically sealed tantalum capacitors with sealed electrolyte
	Reviewed In: 2023	Part 3 type fcst 2 Sec 2 non - Polar
192	IS 8507 (Part 4/Sec 1):1983	Specification for fixed insulated hermetically sealed tantalum capacitors with solid electrolyte Part
	Reviewed In: 2023	4 type FCST 3 Sec 1 polar
193	IS 8872 (Part 2/Sec 1):1979	Specification for variable resistors Part 2 general purpose Sec 1 type vrgic
	Reviewed In: 2018	
194	IS 8872 (Part 2/Sec 2):1979	Specification for variable resistors Part 2 general purpose Sec 2 type VRG 2C
	Reviewed In: 2018	
195	IS 8872 (Part 2/Sec 3):1979	Specification for variable resistors Part 2 general purpose Sec 3 type VRG3C
	Reviewed In: 2018	
196	IS 8872 (Part 2/Sec 4):1979	Specification for variable resistors Part 2 general purpose Sec 4 type vrg4p
	Reviewed In: 2018	
197	IS 8872 (Part 2/Sec 5):1980	Specification for variable resistors Part 2 general purpose Sec 5 type VRG 5C
	Reviewed In: 2018	
198	IS 8872 (Part 2/Sec 6):1980	Specification for variable resistors Part 2 general purpose Sec 6 type VRG 6C
	Reviewed In: 2018	
199	IS 8872 (Part 3/Sec 1):1979	Specification for variable resistors Part 3 precision Sec 1 type VRP 1P
	Reviewed In: 2018	
200	IS 8872 (Part 3/Sec 2):1979	Specification for variable resistors Part 3 precision Sec 2 type VRP 1P
	Reviewed In: 2018	
201	IS 8872 (Part 4/Sec 1):1980	Specification for variable resistors Part 4 preset Sec 1 type VRT 1
	Reviewed In: 2021	
202	IS 8872 (Part 4/Sec 2):1983	Specification for variable resistors Part 4 presents Sec 2 type VRT 2P
	Reviewed In: 2018	
203	IS 8872 (Part 4/Sec 3):1982	Specification for variable resistors Part 4 presets Sec 3 type VRT 3
20.4	Reviewed In: 2018	
204	IS 8872 (Part 4/Sec 4):1984	Specification for variable resistors Part 4 preset Sec 4 type VRT 4 P
	Reviewed In: 2018	
205	IS 8872 (Part 4/Sec 5):1984	Specification for variable resistors Part 4 preset Sec 5 type VRT 5 P
• • • • • • • • • • • • • • • • • • • •	Reviewed In: 2018	
206	IS 8909 (Part 1):1978	Fixed Resistors General Purpose Power - Part I General Requirements and Methods of Tests
20-	Reviewed In : 2015	
207	IS 8909 (Part 2):1978	Specification for fixed resistors general purpose power Part 2 type FRP1
200	Reviewed In : 2021	
208	IS 8909 (Part 3):1978	Specification for fixed resistors general purpose power Part 3 type FRP 2
200	Reviewed In : 2021	
209	IS 8909 (Part 4):1978	Specification for fixed resistors general purpose power Part 4 type FRP 3
212	Reviewed In : 2021	
210	IS 8909 (Part 5):1978	Specification for fixed resistors general purpose power Part 5 type FRP 4
011	Reviewed In : 2021	
211	IS 8943:1978	Guide to the design and use of components intended for mounting on boards with printed wiring
	Reviewed In: 2020 IEC	and printed circuits
212	60321: 1970	Decis annihanna antal testina anno aduras for electronic and electric Decision 11 ADV
212	IS 9000 (Part 18/Sec	Basic environmental testing procedures for electronic and electrical items Part 18 solderABility
	13):1981	test
212	Reviewed In : 2021	Cuidonos for anvironmental tactina Dant O calden A Dilitare ad a citaren e e aldenie de
213	IS 9001 (Part 9):1981	Guidance for environmental testing Part 9 solderABility and resistance to soldering heat
	Reviewed In: 2021	

214	IS 9256 (Part 2):1979	Specification for fixed metallized polyester film dielectric capacitors Part 2 type FCPM 1
	Reviewed In: 2021	
215	IS 9256 (Part 3):1979	Specification for fixed metallized polyester film dielectric capacitors Part 3 type FCPM 2
	Reviewed In: 2021	
216	IS 9302 (Part 1):1979	Characteristics and methods of measurements for sound system equipment Part 1 General
	IEC 268-2 & 1, 1A & 1B	
	Reviewed In: 2001	
217	IS 9302 (Part 2):1979	Characteristics and methods of measurements for sound system equipment Part 2 Amplifiers
	IEC 60368-3	
	Reviewed In: 2001	
218	IS 9302 (Part 3):1981	Characteristics and methods of measurements for sound system equipment Part 3 Microphones
	Reviewed In: 2001	
219	IS 9302 (Part 4):1993	Characteristics and methods of measurements for sound systems equipment Part 4 Loudspeaker
217	Reviewed In: 2002	Characteristics and methods of inecastrements for sound systems equipment fact i Boudspeaker
220	IS 9302 (Part 6):1986	Characteristics and methods of measurements for sound system equipment Part 6 Headphones and
220	IEC 60268-7	head sets
	Reviewed In : 2001	nead sets
221		Characteristics and mothods of measurements for sound outtons a minutest Part 7. Automotic sain
221	IS 9302 (Part 7):1987	Characteristics and methods of measurements for sound system equipment Part 7 Automatic gain
	IEC 60268-8	control devices
222	Reviewed In : 2005	
222	IS 9302 (Part 10):1980	Characteristics and methods of measurements for sound system equipment Part 10 Preferred
	IEC 60268-15	matching values for the inter-connection of sound system components
	Reviewed In: 2001	
223	IS 9414 (Part 1/Sec 1):1979	
	Reviewed In: 2021	positive
224	IS 9414 (Part 1/Sec 2):1979	Detail specification for digital integrated circuits Part 1 nand gate TTL Sec 2 dual 4 input positive
	Reviewed In: 2021	
225	IS 9414 (Part 1/Sec 3):1979	Detail specification for digital integrated circuits Part 1 nand gate TTL Sec 3 triple 3 input positive
	Reviewed In: 2021	
226	IS 9414 (Part 1/Sec 4):1979	Detail specification for digital integrated circuits Part i nand gate TTL Sec 4 quad 2 input positive
	Reviewed In: 2021	
227	IS 9437 (Part 1):1979	Specification for fixed precision resistors Part 1 general requirements and methods of test
	Reviewed In: 2021 IEC	
	60115-5: 1978	
228	IS 9437 (Part 2):1980	Specification for fixed precision resistors Part 2 type FRPR 1
	Reviewed In: 2021	
229	IS 9437 (Part 3):1980	Specification for fixed precision resistors indian standard Part 3 type FRPR 2
	Reviewed In: 2021	1
230	IS 9437 (Part 4):1980	Specification for fixed precision resistors Part 4 type FRPR 3
	Reviewed In: 2021	alternation and the state of th
231	IS 9470:1979	Method of test for the usABility of resistors under pulse conditions
-5.1	Reviewed In: 2018 IEC	
1	60115-1 : 2008	
232	IS 9501 (Part 1):1980	Methods of measurement of electrical characteristics of microcircuits Part 1 digital micro circuits
232	Reviewed In : 2018	17001000 of mediatement of electrical characteristics of interferential art 1 digital infero circuits
233	IS 9501 (Part 2):1980	Methods of measurement of electrical characteristics of microcircuits Part 2 analogue
233	Reviewed In : 2018	microcircuits
234	IS 9512:1980	Guidance for pulse testing of resistors
254	Reviewed In : 2021	Outdance for pulse testing of resistors
235		Specification for plactic film dialectric variable tuning conscitute and 2 Part 1 tests and a constitute of the contract of th
235	IS 9593 (Part 1):1980	Specification for plastic film dielectric variable tuning capacitors grade 2 Part 1 tests and general
	Reviewed In: 2018 IEC	requirements
225	60418-2: 1976	
236	IS 9596:1981	General requirements and classification of tests for micro circuits
	Reviewed In: 2021	
237	IS 9614 (Part 1):1980	Specification for fixed high - Meg resistors Part 1 type FRHM 1
	Reviewed In: 2021	
238	IS 9614 (Part 2):1980	Specification for fixed high - Meg resistors Part 2 type FRHM 2
	Reviewed In: 2021	
239	IS 9614 (Part 3):1980	Specification for fixed high - Meg resistors Part 3 type FRHM 3
I	1	

	Reviewed In: 2021	
240	IS 9638 (Part 2):1984	Specification for fixed polyester film dielectric capacitors for direct current Part 2 type FCPE 1
	Reviewed In: 2021	
241	IS 9638 (Part 3):1985	Specification for fixed polyester film dielectric capacitors for direct current Part 3 type FCPE 2
	Reviewed In: 2021	
242	IS 9638 (Part 4):1984	Specification for fixed polyester film dielectric capacitors for direct current Part 4 type FCPE 3
	Reviewed In: 2021	
243	IS 9779:1981	Sound Level Meters
	IEC 60651	
	Reviewed In: 2001	
244	IS 9807:1981	Life testing of digital microcircuits
	Reviewed In: 2018 IEC	
	60147-4	
245	IS 9816:1981	General requirements and classification of tests for semiconductor devices
	Reviewed In: 2021	

Annexure-II :List of Indian Product Standards

SI. No.	IS No. & Year	Title
1	IS/QC 001001:2000	IEC quality assessment system for electronic components IECQ - Basic rules First Revision
	Reviewed In: 2024 IECQC	
	001001	
2	IS/QC 001002-2:2000	IEC quality assessment system for electronic components IECQ - Rules of procedure Part 2
	Reviewed In: 2024 IECQC	Documentation First Revision
	001002-2: 1998	
3	IS 12970 (Part 1):2010	Semiconductor devices integrated circuits Part 1 general
	Reviewed In: 2021 IEC	
	60748-1:2002	
4	IS 12970 (Part 2):2021	Semiconductor devices - Integrated circuits Part 2 Digital integrated circuits essential ratings and
	IEC 60748-2: 1997	characteristics Sec 1 General
	Reviewed In: 2024 ISO	
	20252: 2019	
5	IS 12970 (Part 3):2021	Semiconductor devices Integrated circuits Part 3 Analogue integrated circuits Superseding 1 IS
	IEC 60748-3: 1994	12970Part 5Sec 1 1991 2 IS 12970Part 5Sec 2 1992 3 IS 12970Part 5Sec 3 1992 4 IS 12970Part
	ISO 20488:2018	5Sec 4 1992 5 IS 12970Part 5Sec 5 1993 6 IS 12970Part 5Sec
6	IS 13247 (Part 1):2021	Passive filter units for electromagnetic interference suppression Part 1 Generic specification First
	IEC 60939-1: 2010	Revision and Superseding 1 IS 3723Part 1 1978 2 IS 3723Part 2 1983 and 3 IS 3723Part 3 1983
	ISO 3823-2:2003	
7	IS 13247 (Part 2):2021	Passive filter units for electromagnetic interference suppression Part 2 Sectional specification
	IEC 60939-2:2005	Passive filter units for which safety tests are appropriate Test methods and general requirements
	ISO 21363 : 2020	First Revision of IS 13247 Part 2
8	IS 14901 (Part 1):2010	Semiconductor devices - Discrete devices and integrated circuits Part 1 general First Revision
	IEC 60747-1: 2006	
	Reviewed In: 2022 IEC	
	60747-1: 2006	
9	IS 14901 (Part 2):2020	Semiconductor Devices Part 2 Discrete Devices Rectifier Diodes First Revision
	IEC 60747-2: 2016	
	IEC 60747-2 : 2016	
10	IS 14901 (Part 5):2004	Semiconductor devices - Discrete devices and integrated circuits Part 5 optoelectronic devices
	IEC 60747-5	
	Reviewed In: 2021 IEC	
	60747-5:1992	
11	IS 14901 (Part 7):2020	Semiconductor Devices Discrete Devices Part 7 Bipolar Transistors First Revision
	IEC 60747-7 : 2010	
	IEC 60747-7:2010	
12	IS 14901 (Part 8):2020	Semiconductor Devices Discrete Devices Part 8 Field-Effect Transistors Second Revision
	IEC 60747-8 : 2010	
	IEC 60747-8 : 2010	
13	IS 15866 (Part 1):2010	Fixed inductors for electromagnetic interference suppression Part 1 generic specification

I	IEC 60938-1:2006	
	Reviewed In : 2021 IEC	
	60938-1:2006	
14	IS/QC 300000:1988	Fixed capacitors for use in electronic equipment generic specification
14	Reviewed In : 2021 IECQC	1 ixed capacitors for use in electronic equipment generic specification
	300000:1982	
15	IS/QC 300100:1988	Fixed capacitors for use in electronic equipment Sectional specification fixed polyethrsylene -
13	Reviewed In: 2021 IECQC	Terephthalate film dielectric metal foil DC capacitor
	300100: 1982	rerephthalate thin dielectric inetal fon De capacitor
16	IS/QC 300201:2000	Fixed capacitors for use in electronic equipment Part 15 blank detail specification fixed tantalum
	Reviewed In: 2021 IECQC	capacitors with solid electrolyte and porous anode assessment level E
	300201: 1984	capacitors with some electroryte and porous anothe assessment level L
17	IS/QC 300301:1993	Fixed capacitors for use in electronic equipment blank detail specification aluminium electrolytic
1	Reviewed In: 2021	capacitors with non - Solid electrolyte assessment level E
	Reaffirmed but not taken up	÷
	for revision IECQC	
	300301: 1985	
18	IS/QC 300401:1988	Fixed capacitors for use in electronic equipment blank detail specification fixed metallized
	Reviewed In: 2021	polyethylene - Terephthalate film dielectric D C capacitors assessment level e
	Reaffirmed but not taken up	
	for revision IECQC	
	300401: 1982	
19	IS/QC 300600:1993	Fixed capacitors for use in electronic equipment - Sectional specification for fixed capacitors of
	Reviewed In: 2021 IECQC	ceramic dielectric class 1
	300600: 1988	
20	IS/QC 300601:1993	Fixed capacitors for use in electronic equipment blank detail specification for fixed capacitors of
	Reviewed In: 2021	ceramic dielectric class 1 assessment level E
	Reaffirmed but not taken up	
	for revision IECQC	
	300601: 1988	
21	IS/QC 300701:1993	Fixed Capacitors for Use in Electronic Equipment Sectional Fixed Capacitors of Ceramic
	Reviewed In: 2021	Dielectric Class 2
	Reaffirmed but not taken up	
	for revision IECQC	
22	300701: 1988	Fined consists of femore in electronic anniquement Continued and ifficultion for fined tental and the
22	IS/QC 300800:1994	Fixed capacitors for use in electronic equipment Sectional specification for fixed tantalum chip
	Reviewed In : 2020 IECQC 300800: 1989	capacitors
23	IS/QC 300801:1993	Fixed capacitors for use in electronic equipment blank detail specification for fixed tantalum chip
23	Reviewed In : 2020	capacitors assessment level E
	Reaffirmed but not taken up	*
	for revision IECQC 300801	
24	IS/QC 301200:1993	Fixed capacitors for use in electronic equipment Sectional specification for fixed metallized
	Reviewed In: 2021	polypropylene film dielectric D C capacitors
	Reaffirmed but not taken up	1 *1 1*
	for revision IECQC	
	301200: 1982	
25	IS/QC 301201:1993	Fixed capacitors for use in electronic equipment - Blank detail specification for fixed metallized
	Reviewed In: 2021	polypropylene film dielectric D C capacitors - Assessment level e
	Reaffirmed but not taken up	
	for revision IECQC	
	301201: 1982	
26	IS/QC 301301:1993	Fixed capacitors for use in electronic equipment blank detail specification for fixed metallized
	Reviewed In: 2021	polypropylene film dielectric A C and pulse capacitors assessment level E
	Reaffirmed but not taken up	
	for revision IECQC	
27	301301: 1987	Photocontrol of the control of the c
27	IS/QC 301800:2001	Fixed capacitors for use in electronic equipment Part 13 Secal specification fixed polypropylene
	Reviewed In: 2020 IECQC	film dielectric metal foil D C capacitors Sec one - General

	301800: 1991	
28	IS/QC 301801:2001	Fixed capacitors for use in electronic equipment Part 13 blank detail specification fixed
	Reviewed In: 2020 IECQC	polypropylene film dielectric metal foil D C capacitors assessment level E
	301801: 1991	
29	IS/QC 302400:1994	Fixed capacitors for use in electronic equipment Sectional specification for fixed capacitors fo
	Reviewed In: 2018 IECQC	
	302400: 1993	
30	IS/QC 400100:1988	Fixed resistors for use in electronic equipment Sectional specification fixed low - Power non -
	Reviewed In: 2021 IECQC	
	400100: 1982	
31	IS/QC 400101:1988	Fixed restors for use in electronic equipment blank detail specification fixed low - Power non -
	Reviewed In: 2021 IECQC	
	400101: 1982	
32	IS/QC 400200:1992	Fixed resistors for use in electronic equipment Sectional specification fixed power resistors
	Reviewed In: 2021 IECQC	
	400200: 1982	
33	IS/QC 400400:1994	Fixed resistors for use in electronic equipment - Sectional specification for fixed resistor network
	Reviewed In: 2021	with individually measurable resistors
	Reaffirmed but not taken up	·
	for revision IECQC	
	400400: 1983	
34	IS/QC 400401:1994	Fixed resistors for use in electronic equipment - Blank detail specification - Fixed resistor
	Reviewed In: 2021	networks with individually measurable resistors all of equal value and equal dissipation assessmen
	Reaffirmed but not taken up	level E
	for revision IECQC	
	400401: 1983	
35	IS/QC 400500:1993	Fixed resistors for use in electronic equipment - Sectional specification for fixed resistor network
	Reviewed In: 2021	in which not all resistors are individually measurable
	Reaffirmed but not taken up	
	for revision IECQC	
	400500: 1984	
36	IS/QC 400501:1994	Fixed resistors for use in electronic equipment - Blank detail specification for fixed resistors
	Reviewed In: 2021	networks in which not all resistors are individually measurable - Assessment level E
	Reaffirmed but not taken up	
	for revision IECQC	
	400501: 1984	
37	IS/QC 400600:1994	Fixed resistors for use in electronic equipment Sectional specification for fixed chip resistors
	Reviewed In: 2021	
	Reaffirmed but not taken up	
	for revision IECQC	
	400600: 1989	
38	IS/QC 400601:1993	Fixed resistors for use in electronic equipment blank detail specification for fixed chip resistors
	Reviewed In: 2021	assessment level E
	Reaffirmed but not taken up	
	for revision IECQC	
	400601: 1989	
39	IS/QC 410100:1992	Potentiometers for use in electronic equipment Sectional specification lead - Screw actuated and
	Reviewed In: 2021	rotary preset potentiometers
	Reaffirmed but not taken up	
	for revision IECQC	
10	410100: 1989	
40	IS/QC 410101:1992	Potentiometers for Use in Electronic Equipment Blank Detail Specification Lead-Screw Actuate
	Reviewed In: 2021	and Rotary Preset Potentiometers Assessment Level E
	Reaffirmed but not taken up	
A 1	for revision IECQC 410101	
41	IS/QC 420000:1994	Varistors for use in electronic equipment - Generic specification
	Reviewed In: 2023 IECQC	
	420000	Varistors for use in electronic equipment -Sectional specification for surge suppression varistor
42	IS/QC 420100:1994	

ı	1	1
	Reviewed In: 2021	
	Reaffirmed but not taken up	
	for revision IECQC 420100	
43	IS/QC 420102:1993	Varistors for use in electronic equipment - Blank detail specification for zinc oxide surge
	Reviewed In: 2021	suppression varistors - AsiEssment level E
	Reaffirmed but not taken up	
	for revision IECQC 420102	
44	IS/QC 440000:1994	Directly heated positive step function temperature coefficient thermistors - Generic specification
	Reviewed In: 2018 IECQC	
	440000	
45	IS/QC 440001:1993	Directly heated positive step function temperature coefficient thermistors - Blank detail
	Reviewed In: 2021	specification - Assessment level E
	Reaffirmed but not taken up	
	for revision IECQC 440001	
46	IS/IEC 60115-2:2023	Fixed resistors for use in electronic equipment Part 2 Sectional specification Low-power film
	IEC 60115-2: 2023	resistors with leads for through-hole assembly on circuit boards THT
47	IS/IEC 60384-4:2016	Fixed capacitors for use in electronic equipment Part 4 Sectional specification Fixed aluminium
	IEC 60384-4: 2016	electrolytic capacitors with solid MnO2 and non-solid electrolyte Superseding IS 4317 1983 and
40	10/10/2004 0 2015	ISQC 300300 1992
48	IS/IEC 60384-9:2015 IEC 60384-9: 2015	Fixed capacitors for use in electronic equipment Part 9 Sectional specification Fixed capacitors of
	IEC 60384-9: 2013	ceramic dielectric Class 2 Superseding IS 2786 Part 1 1978 and ISQC 300700 1994
49	IS/IEC 60384-15:2017	Fixed capacitors for use in electronic equipment Part 15 Sectional specification Fixed tantalum
49	IEC 60384-15: 2017	capacitors with non-solid or solid electrolyte
	IEC 00384-13. 2017	capacitors with non-solid of solid electrolyte
50	IS/IEC 60384-141-1):2016	Fixed capacitors for use in electronic equipment Part 14 Blank detail specification Fixed
	IEC 60384-14-1: 2016	capacitors for electromagnetic interference suppression and connection to the supply mains Section
	ISO 14952-1 : 2003	1 Assessment level DZ Superseding ISQC 302401 1994
51	IS/IEC 62326-1:2002	Printed Boards Part 1 Generic specification
	IEC 62326-1 : 2002	Timou Zonius Turi T Control specification
	Reviewed In: 2024 IEC	
	62326-1 : 2002	
52	IS/IEC 62326-20:2016	Printed Boards Part 20 Printed Circuit Boards for High-Brightness LEDs
	IEC 62326-20 : 2016	
	Reviewed In: 2024 IEC	
	62326-20 : 2016	
53	IS 7305:2018	Fixed capacitors for use in electronic equipment - Generic specification Second Revision
	IEC 60384-1 : 2016	
	Reviewed In: 2021 IEC	
	60384-1:2016	
54	IS/QC 760000:1994	Semiconductor devices - Integrated circuits - Generic specification for film integrated circuits and
	Reviewed In: 2021	hybrid film integrated circuits
	Reaffirmed but not taken up	
	for revision IECQC 760000	
55	IS/QC 760100:1995	Semiconductor devices - Integrated circuits - Sectional specification for film integrated circuits
	Reviewed In: 2021	and hybrid film integrated circuits on the basis of qualification approval procedure
	Reaffirmed but not taken up	
	for revision IECQC 760100	
56	IS/QC 760101:1995	Semiconductor devices - Integrated circuits - Blank detail specification for film integrated circuits
	Reviewed In: 2021	and hybrid film integrated circuits on the basis of qualification approval procedure
	Reaffirmed but not taken up	
	for revision IECQC 760101	
57	IS/QC 760200:1995	Semiconductor devices - Integrated circuits - SectlOnal specification for film integrated circuits
	Reviewed In: 2021	and hybrid film integrated circuits on the basis of the capability approval procedures
	Reaffirmed but not taken up	
50	for revision IECQC 760200	
58	IS/QC 760201:1995 Reviewed In : 2021	Semiconductor devices - Integrated circuits - Blank detail specification for film integrated circuits
	Reviewed III: 2021	and hybrid film integrated circuits on the basis of the capability approval procedures

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`	Semiconductor devices - Integrated circuits - Digital integrated circuits - Blank detail specification
	for HCMOS digital integrated circuits Series 54 74 HC 54 74 HCT 54 74 HCU
Reaffirmed but not taken up	
for revision IECQC 790130	
IS/QC 790131:1995	Semiconductor devices - Integrated circuits - Digital integrated circuits - Blank detail specification
Reviewed In: 2021	for complementary MOS digital integrated circuits Series 4000 Band 4000 Ub
Reaffirmed but not taken up	
for revision IECQC 790131	
IS/QC 790132:1995	Semiconductor devices - Integrated circuits - Digital integrated circuits - Blank detail specification
Reviewed In: 2021	for bipolar monolithic digital integrated circuit gates Excluding Uncommitted Logic Arrays
Reaffirmed but not taken up	
for revision IECQC 790132	
IS/QC 790202:1993	Semiconductor devices - Integrated circuits - Analogue integrated circuits blank detail
Reviewed In: 2021	specification for monolithic integrated operational amplifiers
Reaffirmed but not taken up	
for revision IECQC 790202	
IS 9256 (Part 1):2019	Fixed capacitors for use in electronic equipment Part 1 Sectional specification - Fixed metallized
IEC 60384-2 : 2011	polyethylene terephthalate film dielectric d c capacitors First Revision
Reviewed In: 2022 IEC	
60384-2 :2011	
IS 9638 (Part 1):1980	Specification for fixed polyester film dielectric capacitors for direct current Part 1 general
	requirements and methods of tests
	IS/QC 790131:1995 Reviewed In: 2021 Reaffirmed but not taken up for revision IECQC 790131 IS/QC 790132:1995 Reviewed In: 2021 Reaffirmed but not taken up for revision IECQC 790132 IS/QC 790202:1993 Reviewed In: 2021 Reaffirmed but not taken up for revision IECQC 790202 IS 9256 (Part 1):2019 IEC 60384-2: 2011 Reviewed In: 2022 IEC